Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/719,758	LEE ET AL.
Examiner	Art Unit
David Buttner	1710

	SEARCHED		
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARG (INCLUDING SE	CH NOTES (ARCH STRATEG)	()
	DATE	EXMR
inventor search	5/1/2006	DB
chem ab	5/1/2006	DB
east	5/1/2006	DB